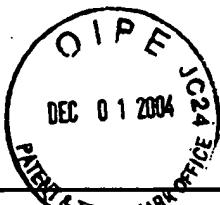


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Substitute for form 1449B/PTO				<i>Complete if Known</i>	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	09/844,271
Sheet 1 of 1				Filing Date	April 30, 2001
				First Named Inventor	THEKKATH
				Group Art Unit	2122
				Examiner Name	Kendall, Chuck
				Attorney Docket Number	MTEC-007/00US

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
CK	1	Embedded Trace Macrocell Specification, Rev. 0/0a, ARM IHI 0014C, ARM Ltd. (1999)	

Examiner Signature	Chuck Kendall	Date Considered	12/22/2004
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U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code ² (if known)		
CC	P1	3,473,154		Couleur et al.	10/14/1969
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² See attached Kinds of U.S. Patent Documents.

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		Office ²	Number ²	Kind Code ³ (if known)			
✓	F1	GB	2 329 048		ARM Limited	10/03/1999	
✓	F2	GB	2 329 049		ARM Limited	10/03/1999	

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